

CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

A2 Global Electronics + Solutions 11701 28th Street North St. Petersburg, FL 33716

Fulfills the requirements of

ISO/IEC 17025:2017

and

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document. The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 22 December 2027 Certificate Number: AT-3054









SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

A2 Global Electronics + Solutions

11701 28th Street North St. Petersburg, FL 33716 Tony Giannetti 800 767 2637

TESTING

ISO/IEC 17025 Accreditation Granted: 11 December 2025

Certificate Number: AT-3054 Certificate Expiry Date: 22 December 2027

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 –

Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to A2 Global Electronics + Solutions to perform the following AS6171 slash sheet tests:

Non-Destructive Testing

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	It <mark>ems, M</mark> aterials or Product Tested	Key Equipment or Technology
Visual Inspection	AS6081, 4.2.6.4 AS6171/2	Electrical, Electronic and	Freedom Scientific HD MAG,Nikon, Vision, Amscope Microscopes.
Solvent Test for Remarking	AS6081 4.2.6.4.3 A AS6171/2		Mineral spirits, Isopropyl alcohol
Dimensional Verification	AS6081, 4.2.6.4.2.2 AS6171/2		Calipers Auto Contactless Measurements
XRF	AS6081, 4.2.6.4.5 AS6171/3	Electronic and Electromechanical (EEE) Components	Multiple X-ray Fluorescence Testing Equipment
X-ray	AS6081, 4.2.6.4.4 AS6171/5	Components	Multiple Radiological Testing Equipment
Scanning Electron Microscopy (SEM) Examination / Inspection	AS6171/2 Method F AS6081 Sect 4.2.6.4.3 C		Scanning Electron Microscope
Acoustic Microscopy	AS6171/6 AS6081 Appendix C.6		Scanning Acoustic Microscope (SAM)







Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation	AS6081, 4.2.6.4.6 AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	Nisene JetEtch Pro, Paragon Oven.
Solderability	ANSI/J-STD-002		Solderability tester RPS 202TL-2 Reflow oven Madell Tech AE-R330
Wetting Balance Solder	ANSI/J-STD-002 MIL-STD-883		Wetting Balance Tester
Plating Thickness	AS6171/3		Plating Thickness Tester
Solvent Test for Resurfacing	AS6081 4.2.6.4.3 B AS6171/2		Hot plate, Acetone, 1-Methyl 2-Pyrrolidinone, Dynasolve 750 (or equivalent).

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test	AS6171/7 Table 2 AS6081, Sect. C.3		
DC Test and Key Parameters AC, Switching, Functional Over Temperature	AS6171/7 MIL-STD-883	Electrical, Electronic and Electromechanical (EEE)	ATE and various Electronic Lab Equipment
DC Test and Key Parameters AC, Switching, Functional Ambient Temperature	AS6171/7 MIL-STD-883	Components	







